U.S. **UTILITY** Patent Application PATENT DATE ART UNIT CONT/PRIOR CLASS . SUBCLASS EXAMINER APPLICATION NO. LAM NGUYEN 09/904919 250 287 Michael Mack Richard Torti. Gas cluster ion beam size diagnostics and workpiece processing TIFE **ISSUING CLASSIFICATION CROSS REFERENCE(S) ORIGINAL** SUBCLASS (ONE SUBCLASS PER BLOCK) CLASS **SUBCLASS CLASS** INTERNATIONAL CLASSIFICATION Continued on Issue Slip Inside File Jacket **CLAIMS ALLOWED DRAWINGS TERMINAL** DISCLAIMER Print Claim for O.G. **Total Claims** Figs. Drwg. Print Fig. Sheets Drwg. NOTICE OF ALLOWANCE MAILED ☐ The term of this patent (date) subsequent to (Assistant Examiner) has been disclaimed. ☐ The term of this patent shall not extend beyond the expiration date **ISSUE FEE** of U.S Patent. No. Date Paid **Amount Due** (Primary Examiner) **ISSUE BATCH NUMBER** The terminal. months of this patent have been disclaimed. (Date) (Legal Instruments Examiner)

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